Total No. of Questions : 8]		SEAT No. :
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B.E. (Electronics & Telecommunication Engineering) VLSI DESIGN & TECHNOLOGY

(2019 Pattern) (Semester - VII) (404182)

			. <i>Marks</i> : 70
		ons to the candidates:	
	<i>1</i>)	Answer Q.1 or Q.2, Q.3 or Q.4, Q.5 or Q.6, Q.7 or Q.8.	
	2) 2)	Neat diagrams must be drawn wherever necessary.	
	3) 4)	Figures to the right indicate full marks. Use of electronic pocket calculator is allowed.	
	<i>5</i>)	Assume suitable data, if necessary.	
Q 1)	a)	Compare CPLD with FPGA.	[8]
	b)	Draw the block diagram of FPGA and explain it in brief.	[9]
		OR	
Q 2)	a)	Explain in brief PLD Design flow	[8]
	b)	Draw the block diagram of CPLD and explain it in brief.	[9]
Q3)	a)	What is technology scaling? Explain any one type of scalin	no with its
23)	u)	effect at least 4 parameters.	[8]
	b)	Explain the working of a transmission gate and implement a cir	rcuit of 4:10
		MUX using transmission gate.	$[10]^{\prime}$
		OR	
Q4)	a)	Draw and explain CMOS inverter transfer characteristics.	[6]
	b)	Explain: Channel Length Modulation, Body Effect, Velocity	saturation.
		8	[12]
<i>O</i> 5)	a)	Explain ASIC Design flow.	[6]
~	b)	Explain DC and transient analysis using SPICE.	[6]
	c)	Explain Antenna Effect in brief.	[6]
	•)	OR OR	[^]
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Q6)	a)	Explain LAMBDA rules used for CMOS layout design.	[6]
*	b)	Write short note on Cross talk.	[6]
	c)	Write SPICE code for CMOS invertor for AC analysis.	[6]
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P.T.O.

Q7) a)	What is DFT? Explain the need for DFT in brief.	[7]
b)	Explain the following terms with respect to testability:	[10]
	i) Fault Models	•
	ii) Fault Models	
	iii) Observability	
	iv) Controllability	
	v) Physical Defects	
	OR	
Q8) a)	What is need of BIST? Explain typical BIST in detail.	[8]
b)	Explain path sensitizing algorithm in detail.	[9]
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